

## INFORMATION DISCLOSURE STATEMENT

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Applicants

Taylor et al.

Filing Date

2004-04-22

Group Art Unit

2419

## U.S. PATENT DOCUMENTS

*EXAMINER INITIALS	CITE NO.	DOCUMENT NUMBER	ISSUE DATE	INVENTOR(S)	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	1.	4905233	1990-02-27	Cain et al.			
	2.	5016244	1991-05-14	Massey, Jr. et al.			
	3.	5408461	1995-04-18	Uriu et al.			
	4.	5544170	1996-08-06	Kasahara, Hiroyuki			
	5.	5548639	1996-08-20	Ogura et al.			
	6.	5559959	1996-09-24	Foglar, Andreas			
	7.	5633859	1997-05-27	Jain et al.			
	8.	5650994	1997-07-22	Daley, Kathleen			
	9.	5856981	1999-01-05	Voelker, John Alvan			
	10.	5894475	1999-04-13	Bruno et al.			
	11.	5936939	1999-08-10	Des Jardins et al.			
	12.	6028863	2000-02-22	Sagawa et al.			
	13.	6038219	2000-03-14	Mawhinney et al.			
	14.	6108300	2000-08-22	Coile et al.			
	15.	6108307	2000-08-22	McConnell et al.			
	16.	6167025	2000-12-26	Hsing et al.			
	17.	6181675	2001-01-30	Miyamoto, Akihiro			
	18.	6181679	2001-01-30	Ashton et al.			
	19.	6185695	2001-02-06	Murphy et al.			
	20.	6195416	2001-02-27	DeCaluwe et al.			

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*EXAMINER INITIALS	CITE NO.	DOCUMENT NUMBER	ISSUE DATE	INVENTOR(S)	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	21.	6259696	2001-07-10	Yazaki et al.			
	22.	6311288	2001-10-30	Hccren et al.			
	23.	6377548	2002-04-23	Chuah, Mooi Choo			
	24.	6424629	2002-07-23	Rubino et al.			
	25.	6456306	2002-09-24	Chin et al.			
	26.	6473398	2002-10-29	Wall et al.			
	27.	6538987	2003-03-25	Cedrone et al.			
	28.	6553015	2003-04-22	Sato, Hiroyuki			
	29.	6556659	2003-04-29	Bowman-Amuah, Michel K.			
	30.	6570846	2003-05-27	Ryoo, In-Tae			
	31.	6581166	2003-06-17	Hirst et al.			
	32.	6590899	2003-07-08	Thomas et al.			
	33.	6594268	2003-07-15	Aukia et al.			
	34.	6643254	2003-11-04	Kajitani et al.			
	35.	6716165	2004-04-06	Flanders et al.			
	36.	6763476	2004-07-13	Dangi et al.			
	37.	6766113	2004-07-20	Al-Salamch et al.			
	38.	6781952	2004-08-24	Shirakawa, Toshikuni			
	39.	6795394	2004-09-21	Swinkels et al.			
	40.	6823477	2004-11-23	Cheng et al.			
	41.	6826184	2004-11-30	Bryenton et al.			
	42.	6829223	2004-12-07	Richardson et al.			
	43.	6862351	2005-03-01	Taylor, William Scott			
	44.	6865170	2005-03-08	Zendle, Allan M.			
	45.	6925578	2005-08-02	Lam et al.			
	46.	6952395	2005-10-04	Manoharan et al.			
	47.	6973034	2005-12-06	Natarajan et al.			
	48.	6981039	2005-12-27	Cerami et al.			

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*EXAMINER INITIALS	CITE NO.	DOCUMENT NUMBER	ISSUE DATE	INVENTOR(S)	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	49.	6983401	2006-01-03	Taylor, William Scott			
	50.	6990616	2006-01-24	Botton-Dascal et al.			
	51.	7027053	2006-04-11	Berndt et al.			
	52.	7093155	2006-08-15	Aoki, Makoto			
	53.	7120148	2006-10-10	Batz et al.			
	54.	7120819	2006-10-10	Gurer et al.			
	55.	7165192	2007-01-16	Cadieux et al.			
	56.	7200148	2007-04-03	Taylor et al.			
	57.	7209452	2007-04-24	Taylor et al.			
	58.	7240364	2007-07-03	Branscomb et al.			
	59.	7275192	2007-09-25	Taylor et al.			
	60.	7350099	2008-03-25	Taylor et al.			
	61.	7460468	2008-12-02	Taylor et al.			
	62.	7466646	2008-12-16	Taylor et al.			

### U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIALS	CITE NO.	DOCUMENT NUMBER	ISSUE DATE	INVENTOR(S)	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	1.	20010000700	2001-05-03	Eslambolchi et al.			
	2.	20020001307	2002-01-03	Nguyen et al.			
	3.	20020072358	2002-06-13	Schneider et al.			
	4.	20020089985	2002-07-11	Wahl et al.			
	5.	20030043753	2003-03-06	Nelson et al.			
	6.	20030051195	2003-03-13	Bosa et al.			
	7.	20030091024	2003-05-15	Stumer, Peggy M.			
	8.	20030128692	2003-07-10	Mitsumori et al.			
	9.	20040090973	2004-05-13	Christie et al.			
	10.	20040125776	2004-07-01	Haugli et al.			

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*EXAMINER INITIALS	CITE NO.	DOCUMENT NUMBER	ISSUE DATE	INVENTOR(S)	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	11.	20040141464	2004-07-22	Taylor et al.			
	12.	20040172574	2004-09-02	Wing et al.			
	13.	20050013242	2005-01-20	Chen et al.			
	14.	20050135237	2005-06-23	Taylor et al.			
	15.	20050135238	2005-06-23	Taylor et al.			
	16.	20050135254	2005-06-23	Taylor et al.			
	17.	20050135263	2005-06-23	Taylor et al.			
	18.	20050138203	2005-06-23	Taylor et al.			
	19.	20050138476	2005-06-23	Taylor et al.			
	20.	20050172160	2005-08-04	Taylor et al.			
	21.	20050172174	2005-08-04	Taylor et al.			
	22.	20050237925	2005-10-27	Taylor et al.			
	23.	20050238006	2005-10-27	Taylor et al.			
	24.	20050238007	2005-10-27	Taylor et al.			
	25.	20050240840	2005-10-27	Taylor et al.			
	26.	20060146700	2006-07-06	Taylor et al.			
	27.	20070168200	2007-07-19	Shimizu, Noriyuki			

### FOREIGN PATENT DOCUMENTS

*Examiner Initials	Cite No.	Document Number	Publication Date	Country	Class	Subclass	Translation	
							Yes	No
	1.							

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	1.	Don Ryan, The Telco Handbook For New Technicians – An Introduction To Telco Technology And Troubleshooting, October 27, 2000, [retrieved from <a href="http://www.darkwing.net/aaron/telco.doc">http://www.darkwing.net/aaron/telco.doc</a> , accessed on November 11, 2006], 67 pages.
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